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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/621,440	KAWAGUCHI, KENICHI	
Examiner	Art Unit	
Daniel Boo	2192	

SEARCHED			
Class	Subclass	Date	Examiner
712	226 245	1/30/2006	DP
MADE	1	8/10/6	2
			
			

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCE)
	DATE	EXMR
west pgp uspat jpoabs epoabs derwent ibm ieee npl 718/105,107 load bal.	1/20/2006	DP
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